Motivating Examples

Tests for exponentiality, uniformity, normality:

Reference: Lockhart, R. A. (1985) The asymptotic distribution of the correlation coefficient in testing fit to the exponential distribution. *The Canadian Journal of Statistics*, **13**, 253–256.

Lockhart, R. A. and M. A. Stephens (1998). The Probability Plot: Tests of Fit Based on the Correlation Coefficient. Chapter 16 in *Handbook of statistics, vol. 17.*Order Statistics: Applications. Eds: N. Balakrishnan, C. R. Rao. Elsevier: Amsterdam.

Why do we do all this mathematics?

Suppose X_1, \ldots, X_n are an iid sample of real rvs.

Notation: F is distribution of individual X_i

Goal: test the hypothesis that F is an Exponential distbn unknown location and scale.

Means $(X_i - \alpha)/\beta$ is standard exponential.

Graphical technique: sort Xs

Get order statistics

$$X_{(1)} < \cdots < X_{(n)}$$

Notice

$$\mathsf{E}(X_{(i)}) = \alpha + \beta m_i$$

where m_i is expected value in standard case.

Plot $X_{(i)}$ against m_i .

Should be straight line.

Measure straightness somehow?

One statistic:

$$T_n = \frac{\text{Error Sum of Squares}}{\widehat{\beta}^2} = n(1 - r^2)$$

where r is usual correlation coefficient.

Reject if T_n too big.

How big? Power? Make distributional approximation? Techniques: 1. Structure of exponential order statistics 2. Parameters known first 3. Slutsky's theorem 4. Martingale central limit theorem

5. Contiguity

Theorem 1 : Let V_1, \ldots, V_n be iid standard exponentials. Put

$$W_i = \alpha + \beta \sum_{j=1}^{i} V_j / (n + 1 - j)$$

Then W_1, \ldots, W_n have the same joint distribution as $X_{(1)}, \ldots, X_{(n)}$.

Proof: Compute joint densities and prove they are equal.

Shows
$$m_i = \sum_{j=1}^i 1/(n+1-j)$$
.

What estimates?

Standard least squares:

$$\widehat{\beta} = \sum_{j=1}^{n} (m_j - \overline{m}) X_{(j)} / \sum_{j=1}^{n} (m_j - \overline{m})^2$$

$$\widehat{\alpha} = \overline{X} - \widehat{\beta}\overline{m}$$

Simplification: $\bar{m} = 1$.

Alternatively: use MLEs.

Now plug in W_i s to get expression in terms of Vs.

Fact: α and β disappear. The statistic is location scale invariant. So study statistic when $\alpha=0$ and $\beta=1$.

Do simpler case first. Don't estimate α , β . Statistic is

$$S_n \equiv \sum (X_{(i)} - m_i)^2$$

Rewrite as

$$S_n = \sum_{i=1}^n \sum_{j=1}^n Q_{ij}(V_i - 1)(V_j - 1)$$

where

$$Q_{ij} = 1/\{n+1-\min(i,j)\}$$

Making distributional approximation. General principle: must stabilize mean and variance (or other location and scale measures).

First

$$\mu_n \equiv \mathsf{E}(S_n) = \sum_{i=1}^n \mathsf{Var}(V_i) Q_{ii}$$
$$= 2 \sum_{i=1}^n 1/i$$
$$= 2 \log(n) + O(1)$$

Goes to infinity so will have to consider

$$S_n - \mu_n$$

Second, put $W_{ij} = (V_i - 1)(V_j - 1)$:

$$\sigma_n^2 \equiv Var(S_n)$$

$$= \sum_{ijkl} Q_{ij} Q_{kl} Cov \left\{ W_{ij}, W_{kl} \right\}$$

The ij,kl covariance is 0 unless the $\{i,j\}=\{k,l\}$.

This leaves the cases:

- 1. i=k, j=l and $i \neq j$. The covariance is $\mathsf{E}\left\{(V_i-1)^2(V_k-1)^2\right\}=1$
- 2. i = l, j = k and $i \neq j$. Again the covariance is 1.
- 3. i = j = k = l. The covariance is $\mathsf{E}\left\{(V_i 1)^4\right\} \mathsf{E}^2\left\{(V_i 1)^2\right\} = 8.$

This makes

$$\sigma_n^2 = 2\sum_{i \neq j} Q_{ij}^2 + 8\sum_i Q_{ii}^2$$

You need to be able to develop approximations for this sort of sum.

Rethink: notice all those covariances which were 0.

Define

$$S_{1,n} = \sum_{i} Q_{ii} (V_i - 1)^2$$

and

$$S_{2,n} = \sum_{i \neq j} Q_{ij}(V_i - 1)(V_j - 1)$$

Let $\mu_{i,n}$ and $\sigma_{i,n}^2$ be the corresponding means and variances.

Note that

$$\mu_{2,n} = 0$$

$$\mu_{1,n} = \mu_n$$

$$\sigma_{2,n}^2 = 2 \sum_{i \neq j} Q_{ij}^2$$

$$\sigma_{1,n}^2 = 8 \sum_i Q_{ii}^2$$

so that $S_{1,n}$ and $S_{2,n}$ are uncorrelated.

Asymptotic formulas.

$$\sigma_{2,n}^2 = 8 \sum_{1}^{n} 1/i^2 \to 8\pi^2/6.$$

$$\sigma_{1,n}^2 = 4 \sum_{1}^{n} (n-i)/(n+1-i)^2$$

$$= 4 \log n + O(1)$$

Off diagonal terms have larger SD so study

$$\frac{S_n - \mu_n}{\sigma_n}$$

Recognize that

$$\frac{S_{1,n} - \mu_n}{\sigma_n} \Rightarrow 0.$$

According to Slutsky's: if

$$\frac{S_{2,n}}{\sigma_n} \Rightarrow Z$$

for some rv Z then

$$\frac{S_n - \mu_n}{\sigma_n} \Rightarrow Z$$

Now how to do $S_{2,n}$?

Structure:

$$S_{2,n} = \sum_{i=2}^{n} A_i(V_i - 1).$$

Note A_i is function of V_1, \ldots, V_{i-1} only. Namely:

$$A_i = 2 \sum_{j=1}^{i-1} Q_{ij}(V_j - 1)$$

For any such structure the terms are uncorrelated!

So: if there is enough independence you might get normality.

In fact if we put

$$M_{k,n} = \sum_{i=2}^{k} A_i(V_i - 1)$$

then for each n

$$M_{2,n}, M_{3,n}, \cdots, M_{n,n}$$

is a martingale.

Use martingale central limit theorem.

Prove

$$\frac{S_{2,n}}{\sigma_n} \Rightarrow N(0,1)$$

Next: consider impact of estimation.

Write Error sum of squares, ESS, as function of parameter values:

$$ESS(\alpha, \beta) = \sum (X_{(i)} - \alpha - \beta m_i)^2$$

Compare $ESS(\hat{\alpha}, \hat{\beta})$ to $ESS(\alpha_o, \beta_o)$.

Use Slutsky several times more.

Example: Now switch from Exponential to Uniform.

Consider again Error Sum of Squares.

(Ie: known parameters first.)

Notation: order statistics of sample are

$$U_{(1)} < \cdots < U_{(n)}$$

Structure: Same distribution as

$$\frac{V_1}{V_1 + \dots + V_{n+1}}, \dots \frac{V_1 + \dots + V_n}{V_1 + \dots + V_{n+1}}$$

for iid exponential Vs.

Error Sum of Squares is ratio N/D where

$$N = \frac{1}{n} \sum_{k=1}^{n} \left(S_k - \frac{k}{n} S_{n+1} \right)^2$$
$$S_k = V + 1 + \dots + V_k$$
$$D = S_{n+1}^2 / n$$

Study behaviour of N because D is like n.

Imagine plotting successive terms in N against k or better, against k/n.

Think of k/n as variable t running from about 0 to about 1.

See factor 1/n as dt.

Formally define function

$$W_n(t) = n^{-1/2} (S_k - (k/n)S_{n+1})$$

where k is the integer part of nt. Then N is exactly

$$\int_0^1 W_n^2(t)dt$$

Weak convergence in $\mathcal{D}[0,1]$: tool to study such objects.

Conclusion

$$\mathsf{ESS} \Rightarrow \sum_{i=1}^{\infty} \lambda_i Z_i^2$$

where Z_i are iid N(0,1) and λ are eigenvalues of integral equation.

Relevant tools: Hilbert space, compact operators on Hilbert space, Gaussian processes, differential equations.

Final version: what about testing for normality?

Statistics produce "asymptotically equivalent" to Shapiro-Wilk statistic.

Put $X_{(k)} = \Phi^{-1}(U_{(k)})$ to relate normal order statistics to uniform.

Use Taylor expansion (delta method) to relate $X_{(k)} - \mathsf{E}(X_{(k)})$ to $S_k - k/n$.

Do delicate analysis for k near 0 or n.

Next: develop relevant tools.